

Tektronix Launches TekScope Anywhere™ to Improve Collaboration, Boost Productivity

New Software Solution Extends Visualization, Analysis and Reporting Capabilities of Tektronix Oscilloscopes to PCs, Tablets

BEAVERTON, Ore., Jan. 27, 2015 /[PRNewswire](#)/ -- Tektronix, Inc., the world's leading manufacturer of oscilloscopes, today announced [TekScope Anywhere™](#), a new software offering that extends the visualization, analysis, and reporting capabilities found on Tektronix oscilloscopes to Microsoft Windows-based PCs, tablets and servers. By decoupling analysis tools from the oscilloscope, engineers can now do much of their work away from the lab and collaborate more effectively with colleagues around the world.

Increasingly, development teams are distributed across multiple geographic areas driving the need for more efficient tools that leverage the cloud and speed up workgroup analysis. TekScope Anywhere™ enables users to collect, analyze and collaborate without being tied to the instruments in their lab. In addition, more analysis is being done prior to arrival of silicon in simulation. For these scenarios, TekScope Anywhere enables measurements on simulation data using the same algorithms that the oscilloscope will use during silicon PHY characterization post-fabrication.

"TekScope Anywhere™ enables our oscilloscope customers to collaborate and work in a more flexible environment," said Brian Reich, general manager Performance Oscilloscopes, Tektronix. "For example, customers can now solve measurement correlation issues across multiple waveform formats from a variety of scopes and simulation environments – independent of the scope hardware."

Collect, Analyze, Collaborate

The use of TekScope Anywhere™ starts with an oscilloscope to collect waveform data and measurement results. From there, a set of common analysis tools are available independent of the hardware used to make the acquisition. A broad set of waveform formats from oscilloscopes or simulation environments are supported including .h5, .wfm, .csv, .bin, .trc, and .tr0.

To speed up analysis, TekScope Anywhere™ features a composite save/recall function to help users get started at the right place every time. An included measurement library offers over 70 measurements, including parametric, jitter, and eye diagrams. Powerful visualizations include waveform and plot displays with interactions for zooming, cursors, and annotations along with math support for basic operations including operands (-, +, etc.), FFT, and arbitrary filters. Advanced jitter measurements are available when equipped with Option DJA.

Session files, including configuration and measurement details, can be saved on any Tektronix [MSO/DPO5000](#), [DPO7000](#), or [MSO/DPO70000](#) series oscilloscope and used within TekScope Anywhere™, eliminating the need to re-configure hardware setups. Adding to its collaboration capabilities, measurement results can be compared simultaneously across multiple waveforms and reports easily generated with the results.

Pricing & Availability

Currently in limited release for evaluation, TekScope Anywhere™ will be available to order in March 2015 worldwide. Pricing starts at \$895 US MSRP. Option DJA for in-depth jitter analysis is priced at \$5,000 US MSRP.

Wondering what else Tektronix is up to? Check out the Tektronix [Bandwidth Banter blog](#) and stay up to date on the latest news from Tektronix on [Twitter](#) and [Facebook](#).

About Tektronix

For more than sixty-five years, engineers have turned to [Tektronix](#) for test, measurement and monitoring solutions to solve design challenges, improve productivity and dramatically reduce time to market. Tektronix is a leading supplier of [test equipment](#) for engineers focused on electronic design, manufacturing, and advanced technology development. Headquartered in Beaverton, Oregon, Tektronix serves customers worldwide and offers award-winning [service](#) and [support](#). Stay on the leading edge at www.tektronix.com.

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